

**MATERIALS RESEARCH SOCIETY**  
**SYMPOSIUM PROCEEDINGS VOLUME 1089**

# **Focused Ion Beams for Materials Characterization and Micromachining**

March 24-28, 2008  
San Francisco, California, USA

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Curran Associates, Inc.  
57 Morehouse Lane  
Red Hook, NY 12571  
[www.proceedings.com](http://www.proceedings.com)

**ISBN: 978-1-60560-876-1**

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